Synthesis of VO₂ Nanowire and Observation of the Metal-Insulator Transition

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Abstract

We have fabricated crystalline nanowires of VO₂ using a new synthetic method. A nanowire synthesized at 650°C shows the semiconducting behavior and a nanowire at 670°C exhibits the first-order metal-insulator transition which is not the one-dimensional property. The temperature coefficient of resistance in the semiconducting nanowire is 7.06 %/K at 300 K, which is higher than that of commercial bolometer.

One dimensional (1-D) nanostructure materials exhibit unique physical properties that differ from their bulk properties. It is due to a characteristic of the 1-D structure such as nanotubes, nanorods, and nanowires [1-3]. It is well-known that an abrupt metal-insulator transition (MIT) and a hysteresis behavior do not occur in 1-D structure. These are an advantage for a device application. Therefore, synthetic efforts for 1-D materials have been continued by many researchers, although synthesis of 1-D structures is very difficult. The transition oxide material, VO₂, undergoes the structural phase transition (SPT) from the monoclinic to the rutile tetragonal structures near 340 K. It was revealed that the first-order MIT is controlled by hole doping of a low density and is not caused by the SPT; this demonstrated the Mott transition [4]. VO₂ has a lot of applications such as electro-optic switch, infrared bolometer, and the Mott first-order field effect transistor (FET), etc. New ideas for the first-order MIT transistor were disclosed by Kim and Kang [5] and Chudnovski et al. [6]. For the fabrication of nanometer-scale Mott FET devices, the synthesis of single-crystalline VO₂ nanowires was reported [7]. Metastable VO₂ nanowire arrays were synthesized via an ethylene glycol reduction approach [8].

In this paper, we reports synthesizing conditions of VO₂ nanowires fabricated by using a synthetic method. Their electrical characteristics are analyzed by measuring the temperature dependence of resistance and I-V characteristics. In particular, to our knowledge, we first observed first-order MITs in nanowires.VO2 nanostructures nanoblock and nanowire were successfully with synthesized by controlling the oxygen partial pressure in the oxidation process of metallic vanadium. The metallic vanadium was grown on α -Al₂O₃ (01-10) substrate at 500 °C in an Ar ambient atmosphere of 50 mTorr using RF Sputter.

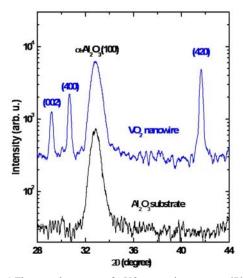


Fig. 1 The crystal structure of a VO₂ nanowire grown at 670 $^{\circ}$ C for 30 minutes. XRD pattern of the VO₂ nanowire compared to JCPDS.

Advantage of this new method is a shorter synthesis time than that of other nanowire fabrication methods such as thermal chemical vapor deposition [9] and the bulk crystal growth method [6]. The use of Al_2O_3 substrate different from SiO₂/Si derived more high quality nanowire on the basis of the fact that VO₂ film is well-grown on Al_2O_3 . Annealing was performed at 630~670 °C in the O₂ ambient atmosphere of 50 mTorr for 30~60 minutes.

Figure 1 shows an X-ray diffraction (XRD) pattern of the crystal structure of a VO₂ nanowire grown at 670 °C for 30 minutes. Lattice constants from XRD peaks are calculated as a=12.03 Å, b=6.693 Å, c=6.42 Å, which is in agreement with the reported values of the monoclinic VO₂ for JCPDS (card No. 71-0042) [10]. (400) peak is the most intense peak of typical VO₂ thin film grown on α -Al₂O₃ substrate.

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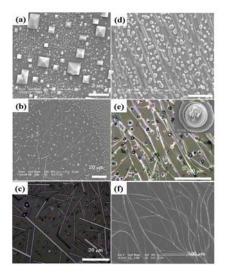


Fig. 2 SEM images of VO₂ nanostructures. The annealing temperatures and times are as follows: (a) 630 °C, (b) 650 °C, (c) 670 °C for 30 min, and (d) 40 min, (e) 50 min, (f) 60 min at 670 °C.

Figure 2 (a)~(c) show high resolution scanning electron microscopy (SEM) images of nanostructures synthesized at several annealing temperatures. The nanostructures are the semblance nanoblocks (quadrangular pyramid) and nanowires. Nanoblocks with a size of 50~500 nm were synthesized at 630 °C. Nanoblocks and wires coexist at 650 °C. Only nanowires were grown at 670 °C. The nanowires in Fig. 2(c) are rectangular parallelepiped form with a length of 10~800 µm (z-axis), a width of 20~150 nm (y-axis) and a thickness of 100~500 nm (x-axis).

Annealing time for fabrication of good nanowires was also changed from 40 to 60 minutes with step of 10 minute, as shown in Fig. 2 (d)~(f). When annealing time was 40 min (Fig. 2(d)), nanowires begin to connect with a neighbor nanowire, and it appear a small nanoblock like a cone form. The inset in Fig. 2(e), it shows a clearly cone form. Annealing time was 1 hour, a nanowire is connected to other nanowires like a crooked bough, as shown in Fig. 2(f). Thus, the optimum growth condition of VO₂ nanowires on Al₂O₃ substrate is found to be at 670 °C and 30 min.

For the VO₂ nanowire grown at 670 °C, the sharp firstorder MIT jump near 347 K and the ohmic behavior above 347 K are exhibited (Fig. 3(a)). The electric field-induced first-order MIT is also measured (Fig. 3(b)). Jump of Current is 1.2×10^{-5} A to 9×10^{-4} A at V_{MIT}=21V and current follows Ohm's law in the larger voltage than V_{MIT}. This indicates that the nanowire has a component of metal. The MIT voltage can be controlled by varying the distance between electrodes of nanowire. The observed first-order MITs are attributed to breakdown of the critical on-site Coulomb interaction between electrons [4,11].

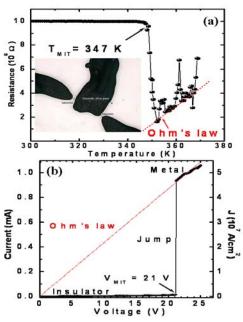


Fig. 3 (a) Temperature dependence of resistance of VO₂ nanowire of grown at 670 $^{\circ}$ C. Inset shows electrode. (b) I-V measurement of VO₂ nanowire. It shows a sharp current jump when an electrical field is applied to nanowire with ~21 V.

In summary, we found conditions fabricating nanowires showing the first-order MIT which is far from the 1-D structural property. Furthermore, the crystalline nanowires with large resistnace are useful to a lot of device applications.

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